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**National Facility for Atom Probe Tomography (NFAPT)**

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**Research Proposal**

1. Name of the project investigator and address:
2. Briefly describe fabrication method and nature of sample: *(max. 50 words)*

*(Metals, semiconductors, ceramics, composites, nanowires, etc.)*

1. Nature of sample:

|  |  |
| --- | --- |
| * Is it magnetic? Yes/No
 | * Is it electron beam sensitive? Yes/No
 |
| * Is it volatile? Yes/No
 | * Is it flammable? Yes/No
 |

1. Motivation for using atom probe tomography, in comparison to other characterization tools: *(max. 100 words)*
2. Nature of work: *(max. 50 words)*

*(Grain boundary/phase boundary/interface analysis, cluster analysis, dopant mapping, etc.)*

1. Is the atom probe sample already prepared?
* *If Yes, please describe the details of preparation method and sample dimensions (max. 50 words)*
* *If No, the type of sample preparation needed. (Electropolishing or Focused Ion Beam)*
1. Is site specific sample preparation mandatory? If so, mention the specific area in the sample.

**Note:**

* Please share results that may be helpful for APT sample preparation and APT analysis

(ex: *SEM and TEM micrographs*)

* Please list one or two APT publications related to this work, if available
* Samples sent to IITM should be in well-polished condition, e.g., suitable for EBSD.